




	Class	Subclass
ISSUE CLASSIFICATION		

NBEST AVAILABLE COPY

PATENT NUMBER

U.S. UTILITY Patent Application

 O.I.P.E. SCANNED  Q.A. 	PATENT DATE
---	-------------

APPLICATION NO.	CONT/PRIOR	CLASS	SUBCLASS	ART UNIT	EXAMINER
09/976739		382	149	2623	J. Matsuo

APPLICANTS
 Christopher Wooten
 Arturo Morosoff

TITLE
 Method for evaluating anomalies in a semiconductor manufacturing process

PTO-2040
 12/89

ISSUING CLASSIFICATION													
ORIGINAL					CROSS REFERENCE(S)								
CLASS		SUBCLASS			CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)							
INTERNATIONAL CLASSIFICATION													

☐ Continued on Issue Slip inside File Jacket

<input type="checkbox"/> TERMINAL DISCLAIMER	DRAWINGS		CLAIMS ALLOWED	
	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims
<input type="checkbox"/> The term of this patent subsequent to _____ (date) has been disclaimed.	_____ (Assistant Examiner)		_____ (Date)	
			NOTICE OF ALLOWANCE MAILED	
ISSUE FEE				
<input type="checkbox"/> The term of this patent shall not extend beyond the expiration date of U.S Patent. No. _____ _____ _____	_____ (Primary Examiner)		_____ (Date)	
			Amount Due	Date Paid
ISSUE BATCH NUMBER				
<input type="checkbox"/> The terminal _____ months of this patent have been disclaimed.	_____ (Legal Instruments Examiner)		_____ (Date)	

WARNING:
The information disclosed herein may be restricted. Unauthorized disclosure may be prohibited by the United States Code Title 35, Sections 122, 181 and 368. Possession outside the U.S. Patent & Trademark Office is restricted to authorized employees and contractors only.

Form PTO-436A
(Rev. 6/99)

FILED WITH: ☐ DISK (CRF) ☐ FICHE ☐ CD-ROM
(Attached in pocket on right inside flap)